Notice of References Cited	Application/Control No. 10/521,227	Applicant(s)/Patent Under Reexamination DAY, IAN EDWARD	
	Examiner Eric Wong	Art Unit 2883	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0039666	02-2006	Knights et al.	385/129
*	B	US-2005/0123227	06-2005	Vonsovici et al.	385/002
*	C	US-6,801,702	10-2004	Day, Ian Edward	385/130
*	D	US-7,020,371	03-2006	Logvin et al.	385/129
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	HEWITT P D ET AL, Improved modulation performance of a silicon p-i-n device by trench isolation, March 2001, Journal of Lightwave Technology IEEE, vol.19 no.3, pages 387-390
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.